

Run-time reconfigurable instruments for advanced board-level testing

Aleksejev, Igor; Jutman, Artur; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 385-392 : ill <https://doi.org/10.1109/AUTEST.2016.7589627>

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Aleksejev, Igor; Jutman, Artur; Devadze, Sergei IEEE instrumentation & measurement magazine 2017 / p. 23-30 : ill <https://doi.org/10.1109/MIM.2017.8006390>